

INTERNATIONAL STANDARD



**Fixed capacitors for use in electronic equipment –
Part 1: Generic specification**

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IEC 60384-1:2016

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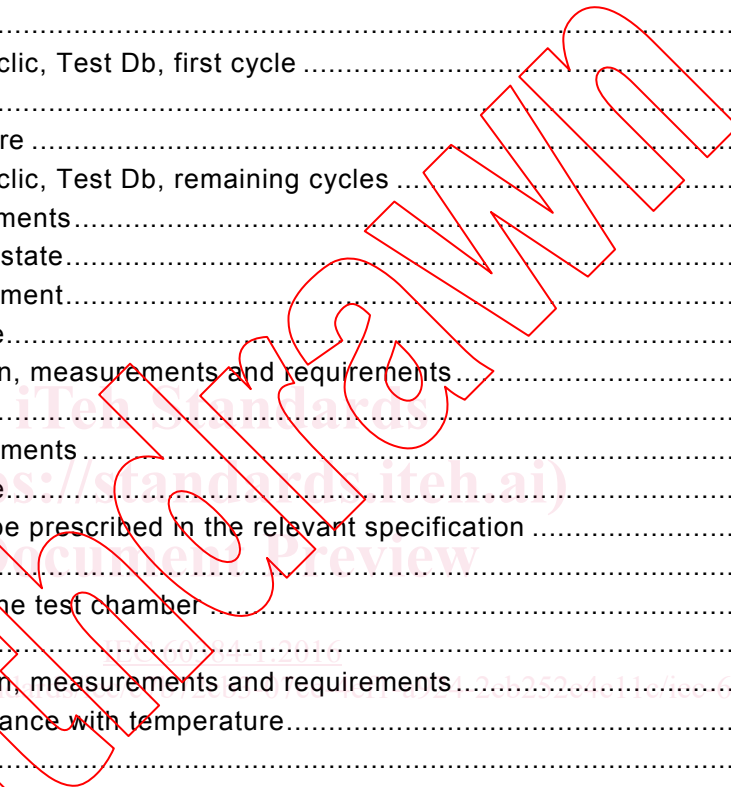
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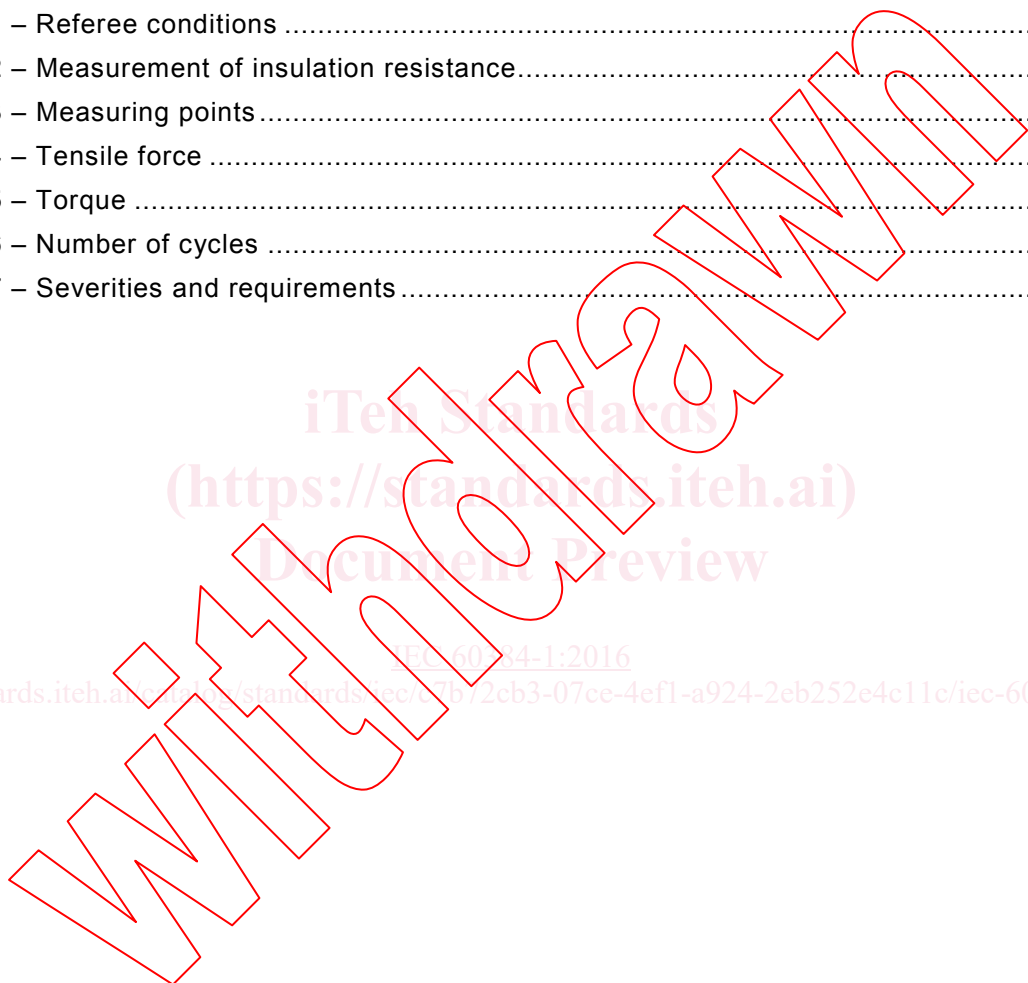
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INTERNATIONAL ELECTROTECHNICAL COMMISSION

FIXED CAPACITORS FOR USE IN ELECTRONIC EQUIPMENT –**Part 1: Generic specification**

FOREWORD

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International Standard IEC 60384-1 has been prepared by IEC technical committee 40: Capacitors and resistors for electronic equipment

This fifth edition cancels and replaces the fourth edition published in 2008 and constitutes a technical revision, including minor revisions related to tables, figures and references.

This edition contains the following significant technical changes with respect to the previous edition:

- INTRODUCTION added;
- 4.41 Whisker growth test added;
- Annex Q completely restructured.

The text of this standard is based on the following documents:

| FDIS | Report on voting |
|--------------|------------------|
| 40/2420/FDIS | 40/2444/RVD |

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

A list of all the parts of the IEC 60384 series, under the general title *Fixed capacitors for use in electronic equipment*, can be found on the IEC website.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

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INTRODUCTION

The specification system for fixed capacitors for use in electronic equipment is structured in a hierarchical system consisting of the following specification types.

Generic specification

The generic specification covers all subjects mainly common to the family of fixed capacitors for use in electronic equipment, such as terminology, methods of measurement and tests. Where the individual subjects require the prescription conditions or parameters specific to the particular subfamily or type of fixed capacitor, such prescriptions are required to be given by one of the subordinate specifications.

For the scope of fixed capacitors, the numeric reference to the generic specification is IEC 60384-1.

Sectional specification

Sectional specifications cover all subjects additional to those given in the generic specification, which are specific to a defined sub-group of fixed capacitors. These subjects normally are preferred values for dimensions and characteristics, additional test methods and relevant prescriptions for test methods given in the generic specification, prescriptions for sampling and for the preparation of specimen, recommended test severities and preferred acceptance criteria. The sectional specification also outlines the structure and scope of the test schedules which are to be applied in all subordinate detail specifications.

For the scope of fixed capacitors, the numeric references to the sectional specifications reach from IEC 60384-2 for polyester film capacitors to currently IEC 60384-26 for aluminium electrolytic capacitors with conductive polymer solid electrolyte. The variety of sectional specifications may be adapted to the portfolio of different technologies of fixed capacitors.

Detail specification

Detail specifications give directly, or by making reference to other specifications, all information necessary to completely describe a given type and range of fixed capacitors, including prescriptions of all values for dimensions and characteristics. They also give all information required for the quality assessment of the covered type and range of fixed capacitors within a suitable quality assessment system, including prescriptions for all applied test severities and acceptance criteria, and the completed test schedules.

Detail specifications can be either specifications within the IEC system, another specification system linked to IEC, or specified by the manufacturer or user. For the scope of fixed capacitors, the numeric references to detail specifications are for example IEC 60384-3-101, if related to the sectional specification IEC 60384-3 and to the ancillary blank detail specification IEC 60384-3-1.

Blank detail specification

The hierarchical system of specifications is supplemented by one or more blank detail specifications to a sectional specification, which are used to ensure a uniform presentation of detail specifications. The blank detail specifications provide the specification writer with a template on the layout to be adopted and on the information to be given and with guidance for the preparation of detail specifications in line with the requirements of the superior generic or sectional specifications. Blank detail specifications are not considered as relevant specifications since they do not themselves describe any particular component.

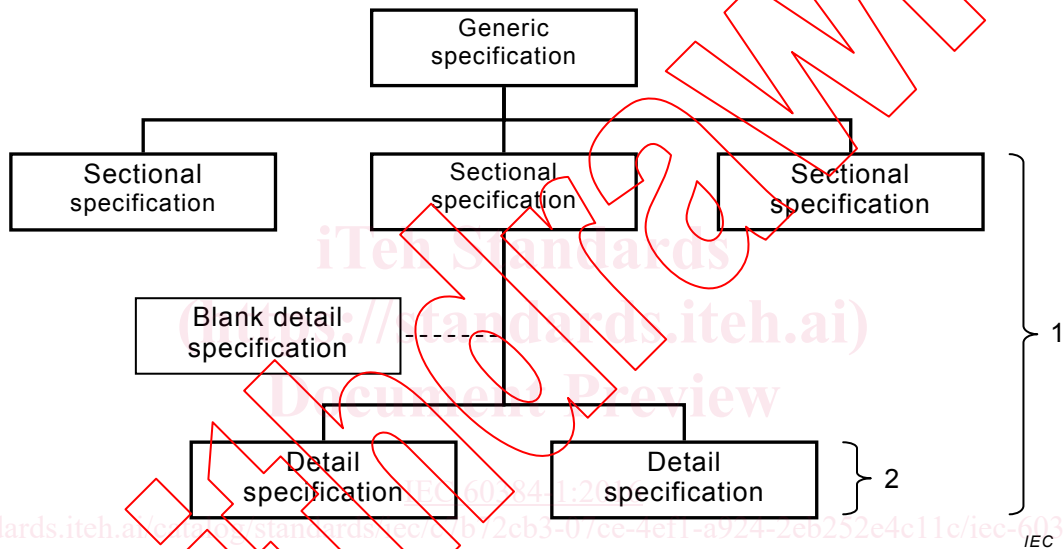
The presence of an established hierarchical specification system with blank detail specifications permits the preparation of detail specifications even outside of the relevant IEC technical committee.

For the scope of fixed capacitors, the numeric references to blank detail specifications are, for example, IEC 60384-3-1, if related to the sectional specification IEC 60384-3.

Relevant specification

In this system the term “relevant specification” addresses subordinate specifications containing specific requirements, where applicable.

Any generic or sectional specification may use abstract and universal references to subordinate specifications of either hierarchical level by use of the expression “relevant specification”.



Key

- 1 Indicates the range of “Relevant specifications” to the superior generic specification, where applicable.
- 2 Indicates the range of “Relevant specifications” to the superior sectional specification, where applicable.